



Introduction
to
Center for Advanced Life Cycle Engineering

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CALCE at University of Maryland

Over 30 Years of CALCE Support of the Electronic Industry

- Research, test and consulting services (contracts through UMD, lab services, consortia membership)
- Over 800 research projects, \$100 million in research funding, and 1000+ published articles) for design, manufacture, life assessment and life management of electronics components, products and systems
- Continuing learning opportunities (more than 300 webinars, 100+ keynotes at conferences, 200+ short courses)
- Skilled engineers (over 300 Ph.D. and 500 M.S. degrees) with sophisticated problem solving skills for design, manufacture and test of reliable products that meet the targeted applications
- Over 500 practicing engineers working for organizations such as Apple, Dell, Google, Honeywell, Intel, Microsoft, NASA, Northrop Grumman, Samsung and Schlumberger

CALCE Clients

- ABB Switzerland Ltd.
- ACell, Inc.
- ACC Electronix
- Advanced Bionics
- Aerojet Rocketdyne
- Agilent Technologies, Inc.
- Allergan
- America II Electronics, Inc.
- American Panel Corporation
- Amazon Web Services
- Anadigics, Inc.
- Ansaldo STS USA, Inc.
- Applied Biometrics
- AprilAire
- ASML
- AST
- ATV Semapp
- Austria Microsystems AG
- Avaya Global Operations
- BAE Systems Electronics & Integrated Solutions
- Baker Hughes Inc.
- Bartlit Beck Herman
- Beijing Weibu Technology Limited Liability Company
- Bloomberg
- Boeing Co.
- Bombardier Aerospace
- Butterfly Networks
- Celestica International
- Chrysler Corp.
- Club
- CNN
- Coch
- Colli
- Cont
- Curti
- Cum
- CSX
- Dakt
- Defe
- Activ
- Dell,
- Delp
- Dow
- Dow
- DFR
- Edm
- Emb
- Emerson
- Electrospec, Inc.
- EMC Corp.
- Fairchild Controls Corp.
- Finisar
- FirstTissues
- Fourth Dimension
- Fujitsu Network Communications
- GE Healthcare Technologies
- General Dynamics Advanced
- NASA Glenn Research Center
- NASA Goddard Space Flight Ctr
- Silicon Powers
- SpaceQuest
- SORAA
- Souriau
- Stratatsys, Inc.
- Stryker
- Stanley Black and Decker
- Sun Metals
- Sunpower
- Team Corp.
- TEKELEC
- Telcare, Inc.
- Trilumia.
- Teradyne, Inc.
- Tessera
- Tintronics Industries
- Toyota Research Institute of N.A.
- Triumph
- TU CIC Virtuhcon
- U.S. Army ARDEC
- U.S. Army CECOM
- U.S. Army Research Lab.
- Unison Industries
- Universal Lighting Technologies
- Vertiv
- Waites
- Whirlpool
- X-Wave

- **Consumer and mobile products**
- **Telecommunications and computer systems**
- **Energy systems (generation/storage/distr)**
- **Industrial systems**
- **Automotive systems**
- **Aerospace systems**
- **Medical systems**
- **Defense systems**
- **Equipment manufacturers**
- **Government Labs and Agencies**

CALCE Mission and Thrust Areas Continue to be Critical

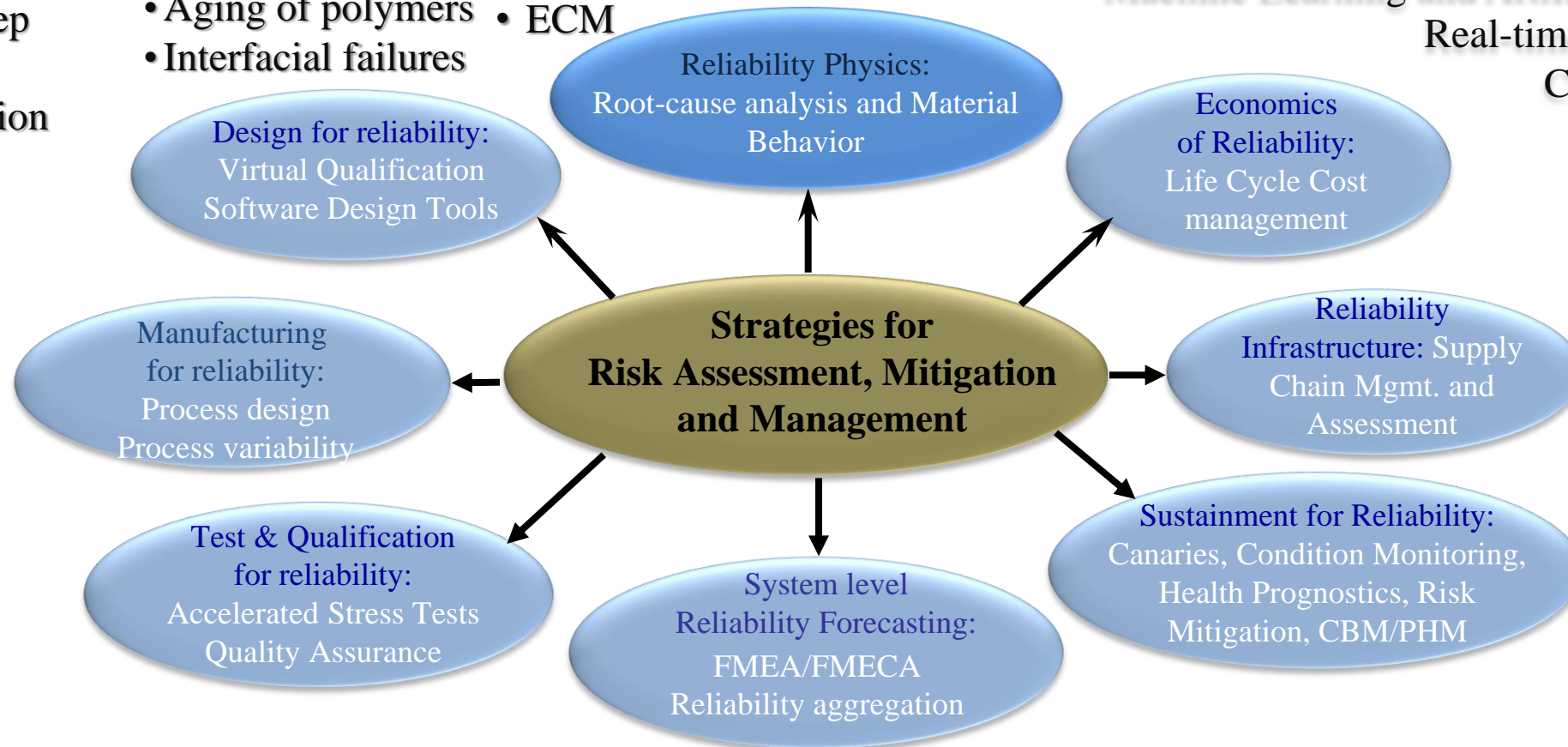
Providing a knowledge and resource base to support the development and sustainment of competitive electronic products

- Fatigue and Fracture
- Plasticity, creep
- Wear/fretting
- Electromigration
- ESD/EOS
- TDDDB

- Whiskers
- Aging of polymers
- Interfacial failures

- Corrosion
- ECM

Machine Learning and Artificial Intelligence
Real-time Data Analytics
Cloud Computing
IoT



Convergence of Reliability-Physics (RP) and Artificial Intelligence (AI)

CALCE Activities

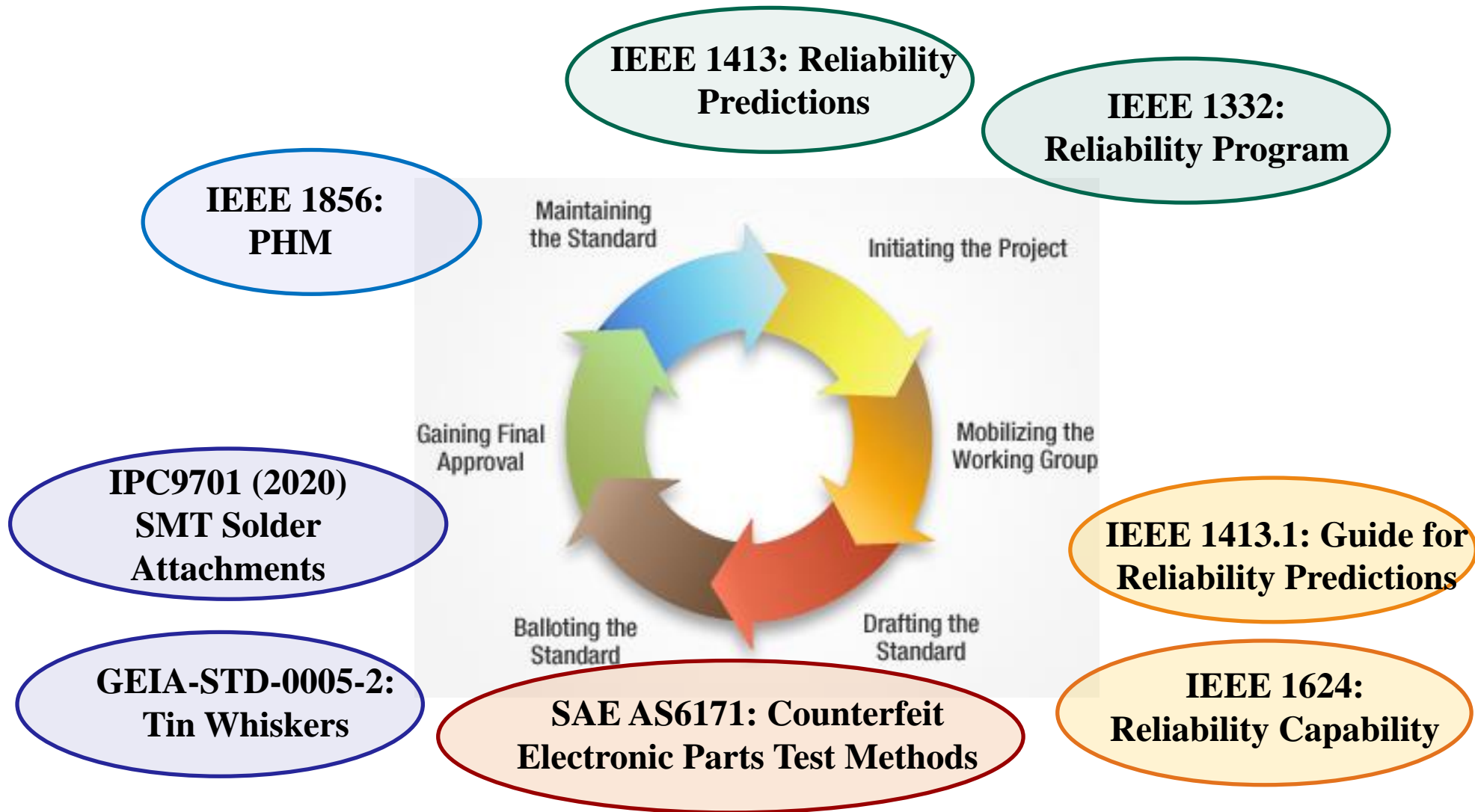
- **Education**
 - University degree programs, on-site customized professional development courses, web based seminars, workshops and symposia.
- **Standards Development**
 - Participation on standards development through societies and organizations such as IEEE, IPC, and SAE
- **Contracts**
 - Research and service contracts with negotiated terms with University.
- **Test Services and Failure Analysis**
 - Design review, simulation assisting product life assessment, material and product testing, supply chain management, and root cause failure identification.
- **Research Consortia**
 - Shared research projects, supplemental projects, access to software and seminars, consulting, and discounts on test services and failure analysis

2022 Symposium on Counterfeit Parts and Materials: June 28-30, 2022 (<https://smta.org/counterfeit>)



- This long-running symposium returns in-person and continues to provide relevant information that can solve problems today while planning for a different business and technology environment in the future. Changes in the electronics supply chain had been fast and furious in the last decades, and its impact on companies' practices is still evolving.
- Join this symposium to present your experience and learn about how the industry is addressing the counterfeit electronics issues we are facing today.
- Abstract Submission Deadline: March 24, 2022
- Contact Dr. Das (diganta@umd.edu) if for more information.

CALCE Standards Development and Leadership



Picture Source: IEEE Standards Association

USPAE DoD Lead-Free Solder Performance and Reliability Assurance Project



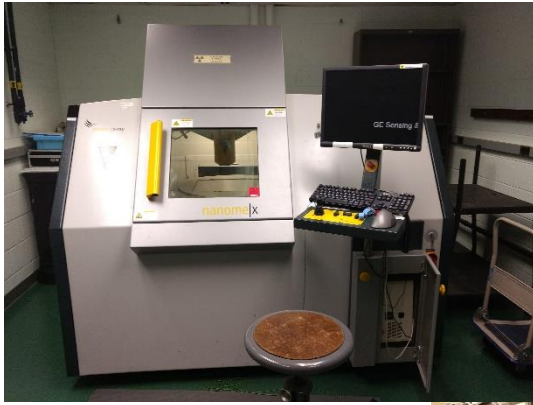
- **Objective:** Provide the technical basis to compare and qualify solder alloys for select defense mission applications.
- **Funding:** \$40 Million, 5 Year Effort, 2021-2025
- **Output:**
 - Solder Performance Specification
 - Solder Users Guide
- **Contact:** Michael Osterman (osterman@umd.edu) for more information

CALCE Fee-For-Service Projects

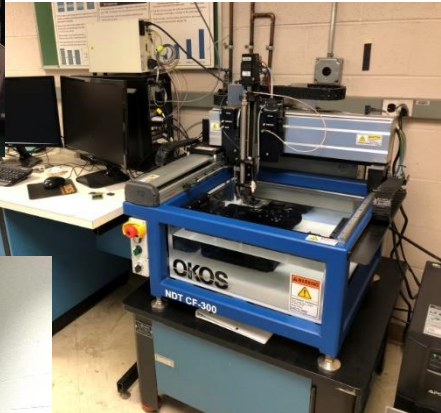
- Projects are developed through discussions with project sponsor.
- Costed Fee-For-Service Project Proposal is submitted to project sponsor
- Projects are initiated when
 - Project sponsor returns signed copy of the costed Fee-For-Service Project Proposal
 - Project sponsor provides payment method – PO, Credit Card
 - Project sponsor provides project materials

Extensive Test and Measurement Labs

CALCE has a sophisticated test and failure analysis laboratory to support research and industry needs.



X-ray Inspection



**Scanning Acoustic
Microscope**



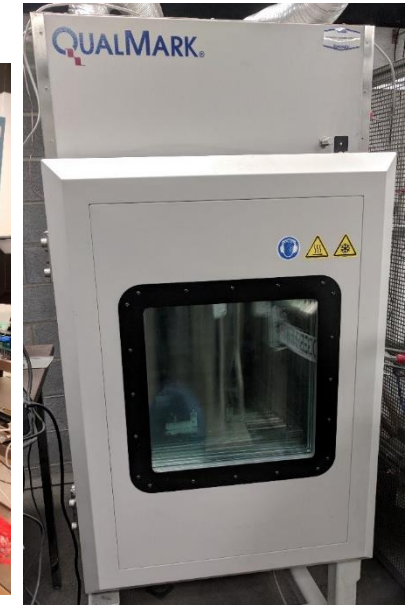
FTIR



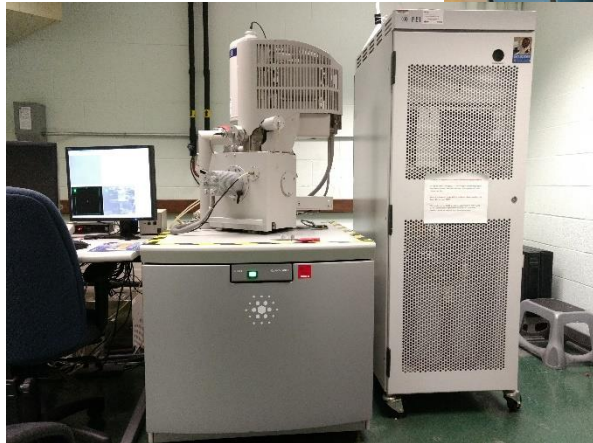
**Thermomechanical
Analyzer**



**Temperature
Cycling Chambers**



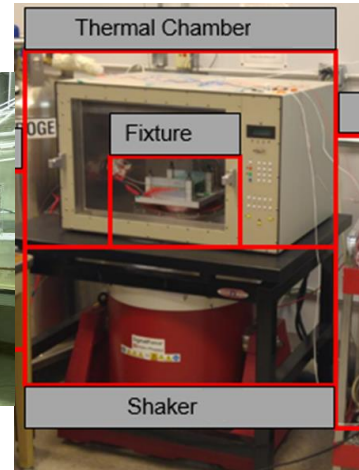
HALT Chamber



**Scanning Electron
Microscope and Energy
Dispersive Spectroscopy**



**Mixed Flowing
Gas Chamber**



**Combined Vib and
Temperature Cycling**

Examples of Fee-for-Service Projects

- Battery Characterization
 - Capacity Measurement
 - Capacity Fade
 - Impedance Measurement
 - Construction Analysis
- Failure Analysis
 - Internal Board Shorts
 - External Board Shorts
 - Solder Interconnect
 - IGBT
- Material Characterization
 - Board Construction
 - Solder Joint/Intermetallic Formation
 - CTE Measurements
 - Plating Thickness
- Simulation/Modeling
 - CALCE SARA Software
- Testing
 - Mixed Flowing Gas
 - Flower of Sulfur
 - Vibration
 - Drop
 - Temperature/Humidity
 - Temperature Cycling
- Training
 - Failure Analysis
 - Physics of Failure Assessments
 - Prognostics and Health Monitoring

CALCE Simulation Assisted Reliability Assessment Software

<https://calce.umd.edu/calce-simulation-assisted-reliability-assessment-sara-software>

Open Access

The image displays several screenshots of the CALCE software interface. The top-left window shows a PCB layout with a green background and a red heat map overlay. The top-right window shows a 3D thermal simulation of the PCB. The middle window shows a 3D wireframe model of the PCB. The bottom-left window shows a detailed view of a component on the PCB. The bottom-right window shows a table of results for a failure mode analysis.

SNo.	Site	#Eval	Prime Failure Model	Damage Criteria	
11.0	U1-solder-open	2.0	1ST_TF_LL	23.96 days (DR:3.48)	Value
			1ST_TF_LL	23.96 days (DR:3.48)	Value
			1ST_TF_LL	23.96 days (DR:3.48)	Value
			1ST_TF_LL	24.95 days (DR:3.33)	Value
			1ST_TF_LL	24.95 days (DR:3.33)	Value
			1ST_TF_LL	24.95 days (DR:3.33)	Value
			1ST_TF_LL	24.95 days (DR:3.33)	Value
			1ST_TF_LL	24.95 days (DR:3.33)	Value
			1ST_TF_LL	121.13 days (DR:0.89)	Value
			1ST_TF_LL	121.13 days (DR:0.89)	Value
			1ST_TF_LL	121.13 days (DR:0.89)	Value
			1ST_TF_LL	169.75 days (DR:0.49)	Value
			1ST_TF_LL	169.75 days (DR:0.49)	Value
			1ST_TF_LL	280.09 days (DR:0.30)	Value
			1ST_TF_LL	280.09 days (DR:0.30)	Value
			1ST_TF_LL	280.09 days (DR:0.30)	Value

Diagram labels: Conductor I, Whisker, Conductor II, Spacing (I₁)

Assembly, Package and Device Failure Assessment Modules

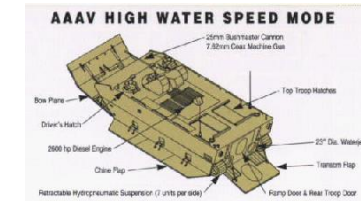
GM

83% reduction in design issues
>10% reduction in time to market



AAAV

Virtual Qualification of circuit cards providing life expectancy



Honeywell

Virtual qualification of engine Controller identified life limiting design issues



Rockwell Collins

Identified design life issue saving customer an estimated \$27 million dollars



CALCE EPS Consortium Research Program

Research Roadmap Thrust Areas

Road Maps

Research Program Theme

(Identification and development of technologies, methodologies, and guidelines for assessing, mitigating, and managing the risks associated with the design, manufacture and fielding of electronic products and systems)

Failure
Identification and
Reliability
Modeling

Environmental
and Operational
Assessment of
Products

Risk-informed
Technology
Insertion
Methodologies

New Technologies, Materials
and Processes

Failure Mechanism

Power and High Temperature
Electronics

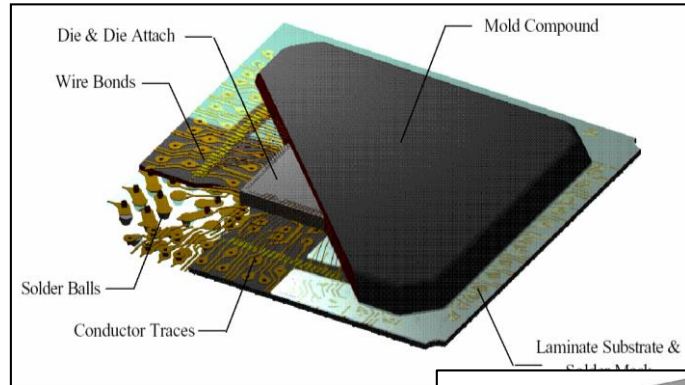
Prognostics, AI and Machine
Learning

Part Management and
Sustainment

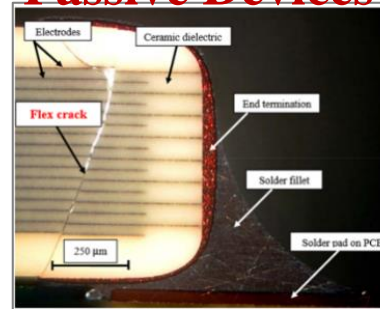
Reliability of Electronic Devices and Interconnects

CALCE Team: M. Azarian, D. Das, A. Dasgupta, B. Han, P. McCluskey, M. Osterman, M. Pecht, and P. Sandborn

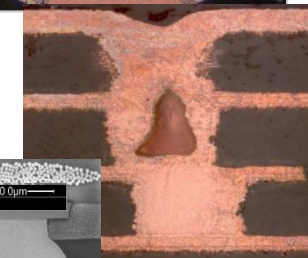
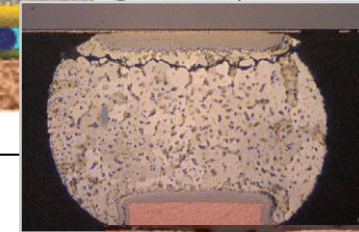
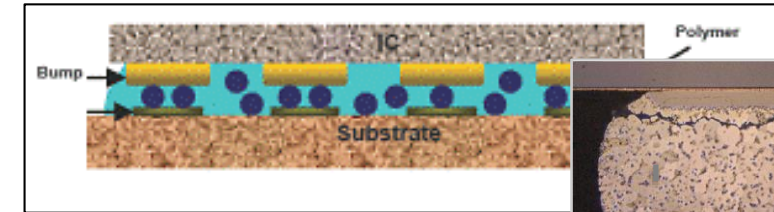
Active Devices



Passive Devices



Interconnects



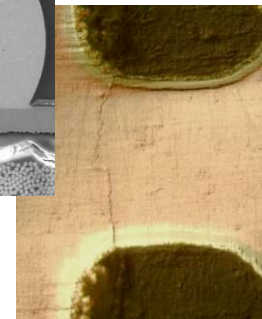
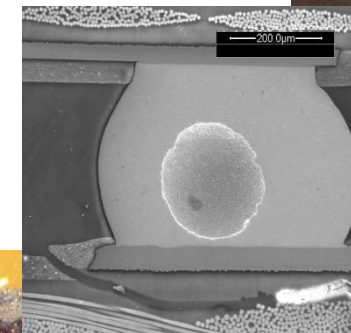
Reliability models and acceleration models can use physics-based and data-based models



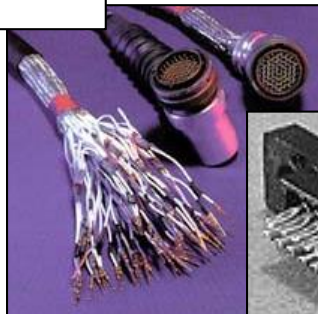
Adhesives



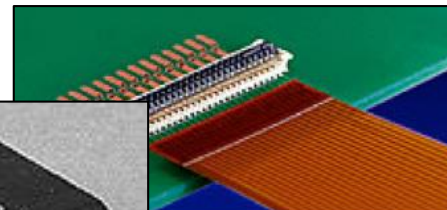
Printed Electronics



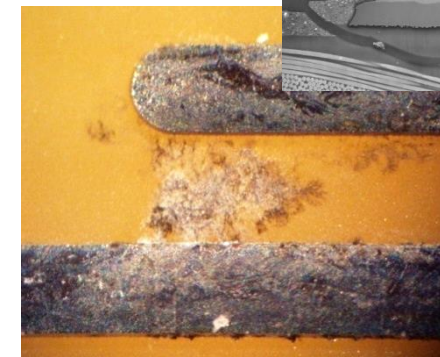
Batteries



Cables & Connectors

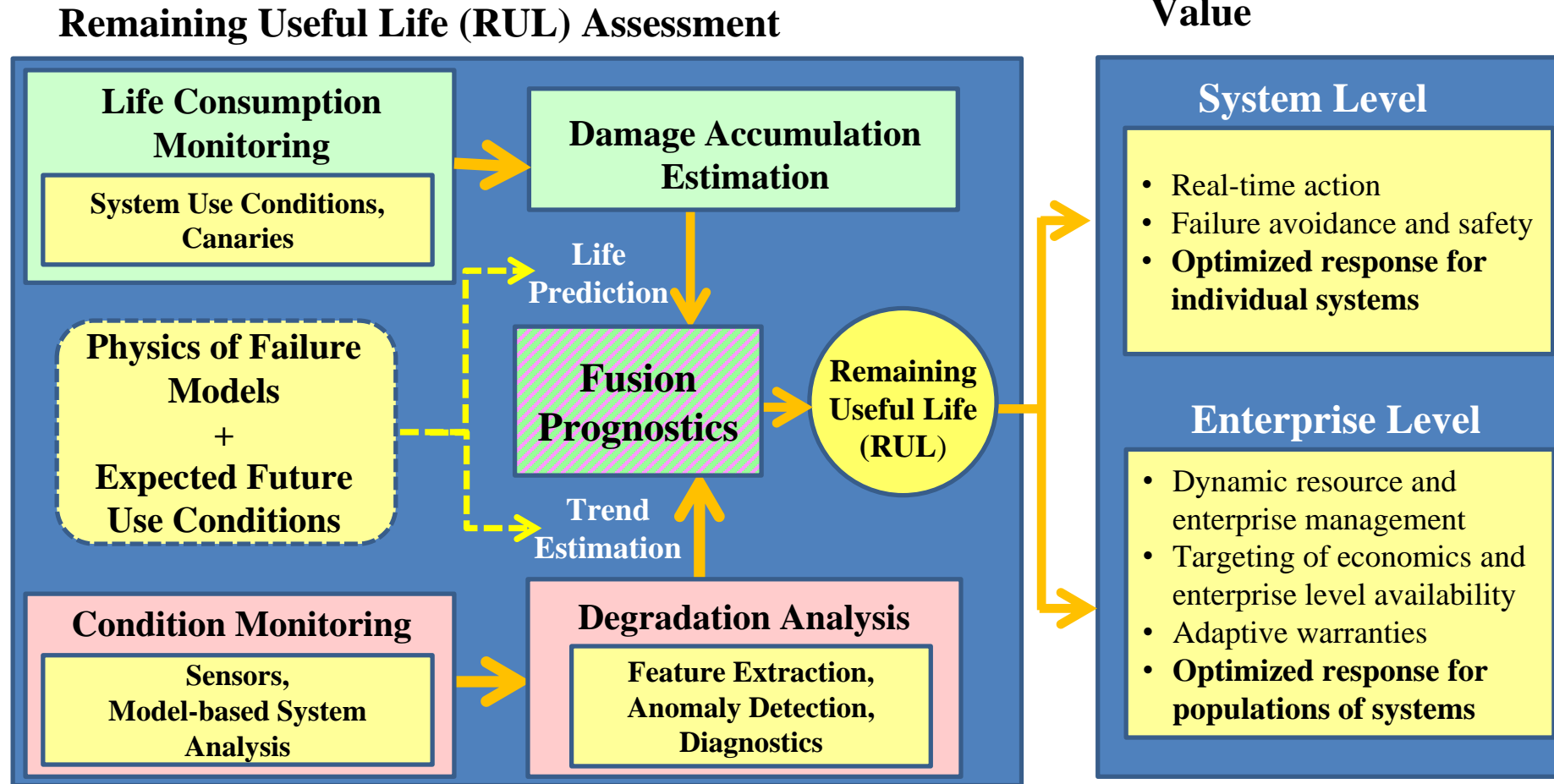


High-Density Substrates



Prognostics and Health Management

CALCE Team: M.H. Azarian, D. Das, A. Dasgupta, P. McCluskey, M. Osterman, M. Pecht, P. Sandborn



CALCE Consortium 2022 Projects

C22-02 Effect of Driving Conditions on Accumulated Solder Joint Damage

C22-03 Fatigue under Multiaxial Cyclic Creep in Oligocrystalline SAC Solder Joints

C22-07 Reliability of Low Temperature (e.g. BiSn) Solder Interconnects

C22-08 Reliability of Third Generation Solder Interconnects

C22-19 Derating and Rapid Assessment of Multilayer Ceramic Capacitors (MLCCs) for Use with Ripple Current

C22-14 Component Life Assessment Methodology Development

C22-15 Paint Durability for Electronic Products

C22-22 Evaluation and Selection of Lubricants for Mechanical Interfaces

C22-12 Development of an IGBT Testing and Screening Procedure

Benefits of Consortium Membership

<https://calce.umd.edu/join-calce-eps-consortium>

- Participation in current consortium research projects
- Input into consortium research roadmap
- Shared access to results from over \$100 million in research
- Technical exchange with other members
- Access to CALCE web site
- Advanced access to latest CALCE Simulation Assisted Reliability Assessment software and software support (EPSC)
- Attendance at semiannual CALCE technical meetings
- Access to CALCE instructional information
- Interaction with CALCE graduate students
- Technical consulting with CALCE Research Staff
- Involvement in the CALCE internship program
- Discount on lab services and CALCE sponsored events

Agenda Tuesday March 22

10:00 am Research Presentations – Session 1

- Derating and Rapid Assessment of Multilayer Ceramic Capacitors (MLCCs) for Use with Ripple Current
- Evaluation and Selection of Lubricants for Mechanical Interfaces
- Long Term Storage Reliability of Hybrid and Polymer Aluminum Electrolytic Capacitors
- Reliability Challenges of Wide Bandgap and Ultra-Wide Bandgap Semiconductor Electronics in Extreme Environments
- Development of an Insolated-Gate Bipolar Transistor (IGBT) Testing and Screening Procedure
- Component Life Assessment Methodology Development

1:00 pm Research Presentations – Session 2

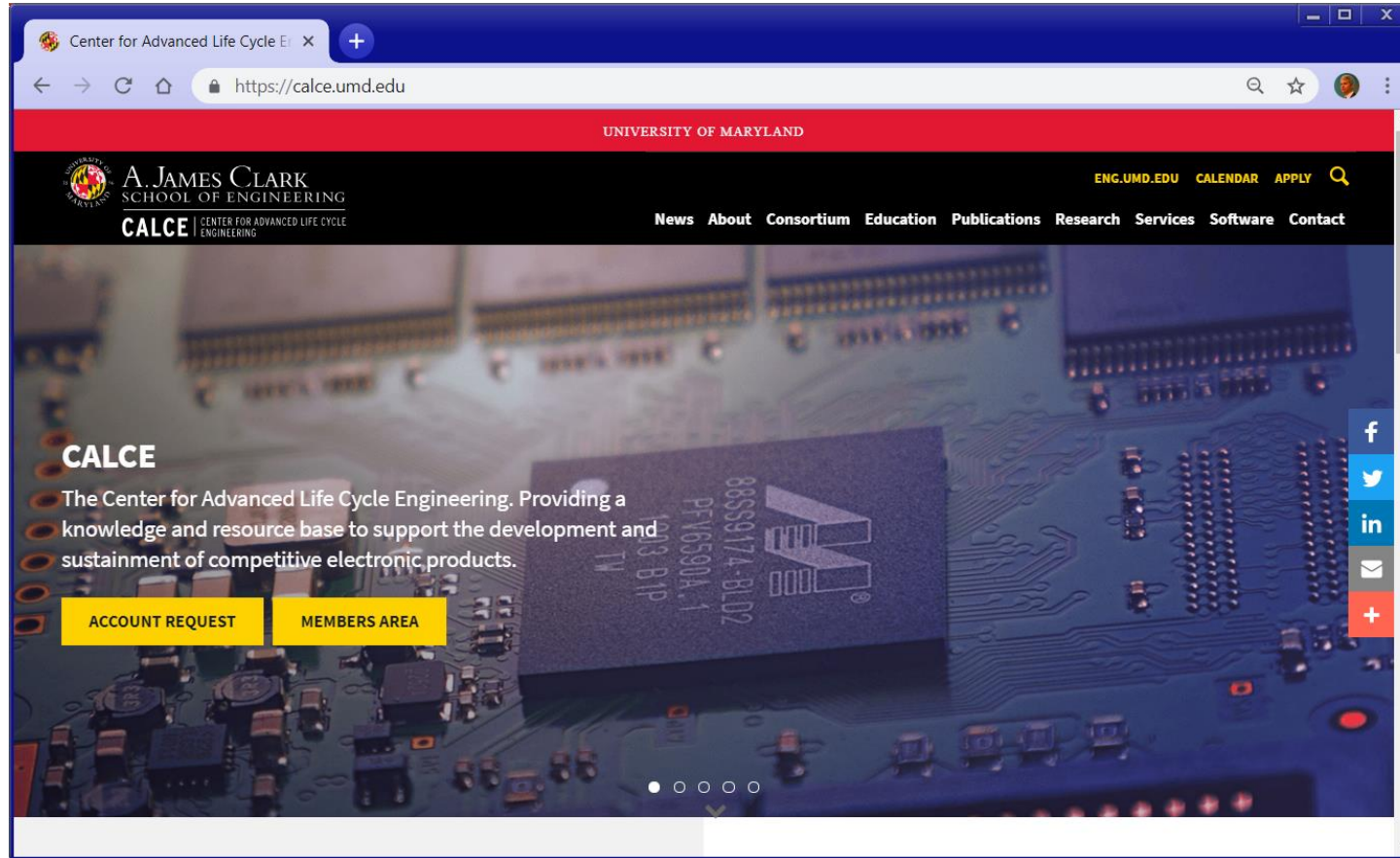
- Enterprise Network Modeling for Counterfeit Part Disruption
- Effect of Driving Conditions on Accumulated Solder Joint Damage
- Reliability of Low Temperature and 3rd Generation Solder Interconnects
- Modeling Solder Interconnect Damage for Complex Temperature Cycles
- Fatigue under Multiaxial Cyclic Creep in Oligocrystalline SAC Solder Joints
- Paint Durability for Electronic Products

Agenda – Wednesday March 23

10:00 am Student Presentations

- Explainable AI for PHM
- Reliability and Safety Analysis using Digital Twins
- Machine Learning and Machine Vision: Applications to Counterfeit Detection
- Water Ingress Protection Testing and Assessment of Portable Electronics
- Electrolyte Influence on Lithium Dendrite Formation
- Are current vibration qualification methods adequate for multiaxial vibration environments ?
- Creep behavior of micron-scale porous sintered silver features seen in high-temperature interconnects and in 3D printed conductors
- Durability of 3D printed electronics under extreme drop conditions
- Additively-fabricated flexible temperature and humidity sensors made from CNT/GO Inks
- Compound failure modes in SMT interconnects under combined vibration and temperature cycling
- Failure Manifestation for Power Electronics Modules

Questions



<https://calce.umd.edu/>
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